Docket No.

265060US0PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Shinji SAKASHITA, et al.

SERIAL NO: New U.S. PCT Application Based on PCT/JP03/01213

GAU:

FILED:

Herewith

EXAMINER:

FOR:

TITANIUM ALLOYS EXCELLENT IN HYDROGEN ABSORPTION-RESISTANCE

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

Applicant(s) wish to disclose the following information.

REFERENCES

EF	ERENCES
	The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
	a six at a disc the amount required under 37 CFR §1.17(p).

☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

ŒL.	ATED CASES
	Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
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☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

EK	TIFICATION	t sited i	n any co	mmunication
	Each item of information contained in this information disclosure statement was fi from a foreign patent office in a counterpart foreign application not more than three	e months	prior to	the filing of
	this statement.			

□ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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LIST OF REFERENCES CITED BY APPLICANT				Shinji SAKASHITA, et al.				
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STATEMENT OF RELEVANCY

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1) References <u>AO-AR</u> have been cited in the International Search Report. Copies of these references are being submitted herewith only when not automatically provided by the International Searching Authority.
2) References have been cited in the corresponding Search Report. A copy of these references is being submitted herewith.
3) References AS, AT are discussed in the specification. A copy of these references is being submitted here with.
4) References are additional prior art known to Applicant. A copy of these references is being submitted herewith.
JP 2824174 PURPOSE: To provide a titanium material exhibiting excellent hydrogen absorption resistance in an aq. Hydrogen sulfide soln. CONSTITUTION: The surface of a cold rolled titanium material is partially coated with titanium carbide, titanium nitride or titanium carbonitride by less than or equal to 1.0% of the total surface area to obtain the objective titanium material excellent in hydroge absorption resistance in an aq. Hydrogen sulfide soln. The surface of the titanium material to be coated is preferably free from flaws having greater than or equal to 10μ m depth and has less than or equal to 3.0μ m surface roughness Rmax. The surface of the titanium carbide, titanium nitride or titanium carbonitride on the surface of the titanium material acts as an active side and a reaction represented by the formula $2H2S+2e \rightarrow 2HS$ - actively takes place.
JP 7-3364 PURPOSE: To develop a titanium pipe exhibiting excellent hydrogen absorbing

PURPOSE: To develop a titanium pipe exhibiting resistance in an aq. Hydrogen sulfide soln.

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STATEMENT OF RELEVANCY

JP 7-3364 cont.

CONSITITUTION: In this titanium pipe, the films of titanium carbide, titanium nitride and (or) titanium carbon nitride are not present on the surface, the inside stress is regulated to <8 kgf/mm2 or (and) the grain size is regulated to 15 to 100μ m. When titanium carbide, titanium nitride and titanium carbon nitride are present on the surface, the surface part forms an activating point, and the reaction of $2H2S+2e\→H2+2HS-$ is vigorously generated. The inside stress and grain size are also important factors for hydrogen absorbing resistance in an aq. Hydrogen sulfide soln.